

**16A, 50V, 0.047 Ohm, Logic Level,  
N-Channel Power MOSFETs**

These are N-Channel logic level power MOSFETs manufactured using the MegaFET process. This process, which uses feature sizes approaching those of LSI integrated circuits gives optimum utilization of silicon, resulting in outstanding performance. They were designed for use with logic level (5V) driving sources in applications such as programmable controllers, automotive switching, switching regulators, switching converters, motor relay drivers and emitter switches for bipolar transistors. This performance is accomplished through a special gate oxide design which provides full rated conductance at gate biases in the 3V to 5V range, thereby facilitating true on-off power control directly from logic circuit supply voltages.

Formerly developmental type TA09871.

**Ordering Information**

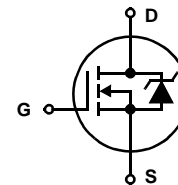
PART NUMBER	PACKAGE	BRAND
RFD16N05L	TO-251AA	RFD16N05L
RFD16N05LSM	TO-252AA	RFD16N05LSM

NOTE: When ordering, include the entire part number. Add the suffix 9A to obtain the TO-252AA variant in tape and reel, i.e. RFD16N05LSM9A

**Features**

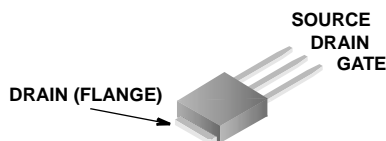
- 16A, 50V
- $r_{DS(ON)} = 0.047\Omega$
- UIS SOA Rating Curve (Single Pulse)
- Design Optimized for 5V Gate Drives
- Can be Driven Directly from CMOS, NMOS, TTL Circuits
- Compatible with Automotive Drive Requirements
- SOA is Power Dissipation Limited
- Nanosecond Switching Speeds
- Linear Transfer Characteristics
- High Input Impedance
- Majority Carrier Device
- Related Literature
  - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

**Symbol**

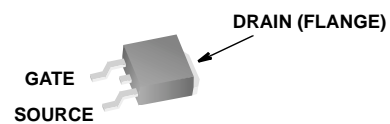


**Packaging**

JEDEC TO-251AA



JEDEC TO-252AA



## RFD16N05L, RFD16N05LSM

### Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ , Unless Otherwise Specified

	RFD16N05L, RFD16N05LSM	UNITS
Drain to Source Voltage (Note 1) . . . . .	50	V
Drain to Gate Voltage ( $R_{GS} = 20k\Omega$ ) (Note 1) . . . . .	50	V
Continuous Drain Current . . . . .	16	A
Pulsed Drain Current (Note 3) . . . . .	45	A
Gate to Source Voltage . . . . .	$\pm 10$	V
Maximum Power Dissipation . . . . .	60	W
Derate Above $25^\circ\text{C}$ . . . . .	0.48	W/ $^\circ\text{C}$
Operating and Storage Temperature . . . . .	-55 to 150	$^\circ\text{C}$
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10s . . . . .	300	$^\circ\text{C}$
Package Body for 10s, See Techbrief 334 . . . . .	260	$^\circ\text{C}$

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1.  $T_J = 25^\circ\text{C}$  to  $125^\circ\text{C}$ .

### Electrical Specifications $T_C = 25^\circ\text{C}$ , Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS	
Drain to Source Breakdown Voltage	$BV_{DSS}$	$I_D = 250\text{mA}$ , $V_{GS} = 0\text{V}$ , Figure 10	50	-	-	V	
Gate to Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}$ , $I_D = 250\text{mA}$ , Figure 9	1	-	2	V	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 40\text{V}$ , $V_{GS} = 0\text{V}$	-	-	1	$\mu\text{A}$	
		$T_C = 150^\circ\text{C}$	-	-	50	$\mu\text{A}$	
Gate to Source Leakage Current	$I_{GSS}$	$V_{GS} = \pm 10\text{V}$ , $V_{DS} = 0\text{V}$	-	-	100	nA	
Drain to Source On Resistance (Note 2)	$r_{DS(ON)}$	$I_D = 16\text{A}$ , $V_{GS} = 5\text{V}$	-	-	0.047	$\Omega$	
		$I_D = 16\text{A}$ , $V_{GS} = 4\text{V}$	-	-	0.056	$\Omega$	
Turn-On Time	$t_{(ON)}$	$V_{DD} = 25\text{V}$ , $I_D = 8\text{A}$ , $V_{GS} = 5\text{V}$ , $R_{GS} = 12.5\Omega$ Figures 15, 16	-	-	60	ns	
Turn-On Delay Time	$t_{d(ON)}$		-	14	-	ns	
Rise Time	$t_r$		-	30	-	ns	
Turn-Off Delay Time	$t_{d(OFF)}$		-	42	-	ns	
Fall Time	$t_f$		-	14	-	ns	
Turn-Off Time	$t_{(OFF)}$		-	-	-	100	ns
Total Gate Charge	$Q_g(TOT)$	$V_{GS} = 0\text{V}$ to $10\text{V}$	$V_{DD} = 40\text{V}$ , $I_D = 16\text{A}$ , $R_L = 2.5\Omega$ Figures 17, 18	-	-	80	nC
Gate Charge at 5V	$Q_g(5)$	$V_{GS} = 0\text{V}$ to $5\text{V}$		-	-	45	nC
Threshold Gate Charge	$Q_g(TH)$	$V_{GS} = 0\text{V}$ to $1\text{V}$		-	-	3	nC
Thermal Resistance Junction to Case	$R_{\theta JC}$		-	-	2.083	$^\circ\text{C/W}$	
Thermal Resistance Junction to Ambient	$R_{\theta JA}$		-	-	100	$^\circ\text{C/W}$	

### Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage	$V_{SD}$	$I_{SD} = 16\text{A}$	-	-	1.5	V
Diode Reverse Recovery Time	$t_{rr}$	$I_{SD} = 16\text{A}$ , $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	125	ns

NOTES:

2. Pulse Test: Pulse Width  $\leq 300\text{ms}$ , Duty Cycle  $\leq 2\%$ .
3. Repetitive Rating: Pulse Width limited by max junction temperature.

Typical Performance Curves Unless Otherwise Specified

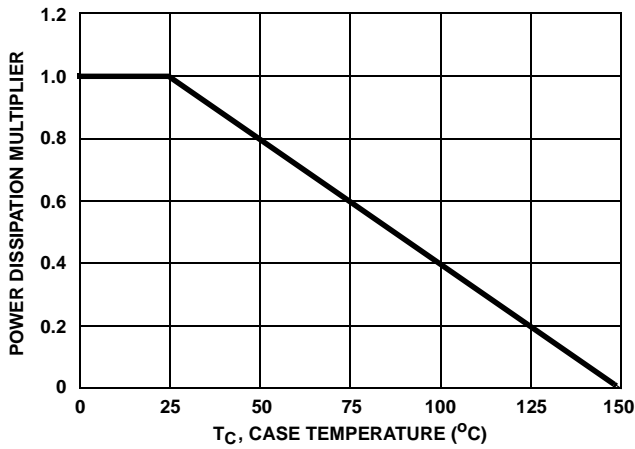


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

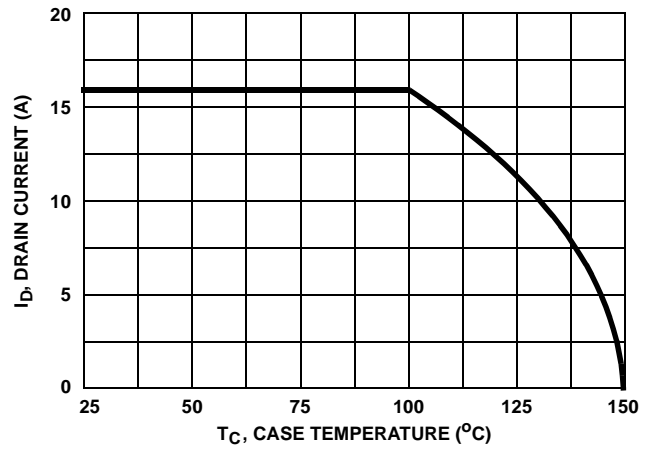


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

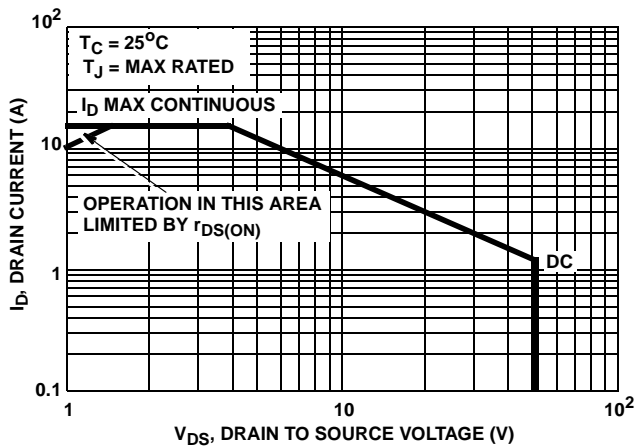


FIGURE 3. FORWARD BIAS SAFE OPERATING AREA

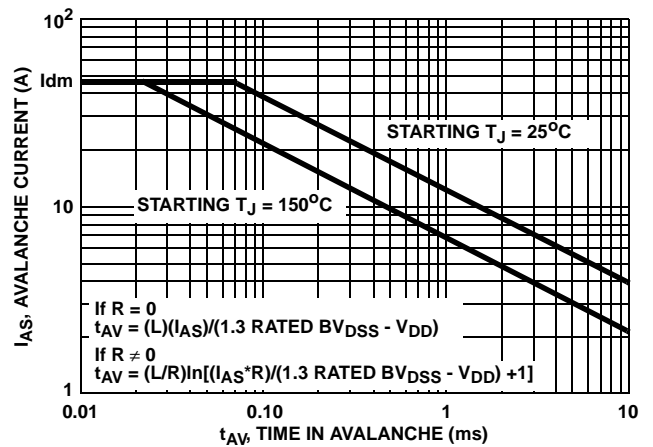


FIGURE 4. UNCLAMPED INDUCTIVE SWITCHING SOA (SINGLE PULSE UIS SOA)

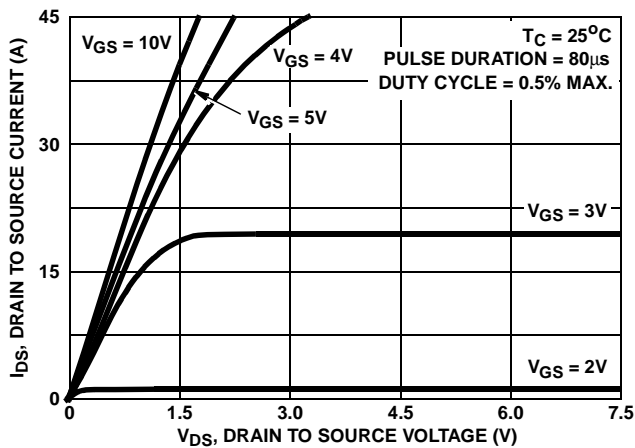


FIGURE 5. SATURATION CHARACTERISTICS

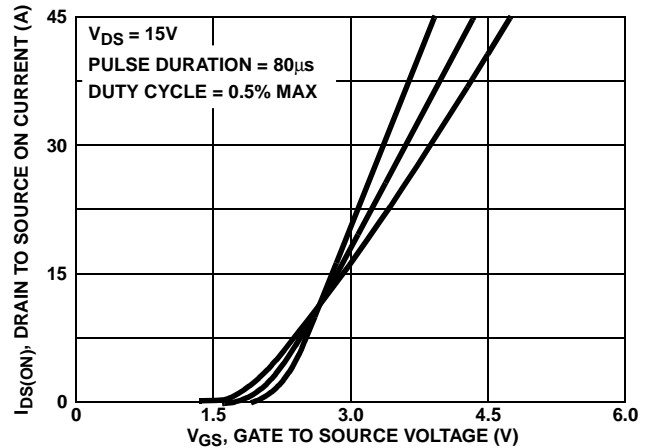


FIGURE 6. TRANSFER CHARACTERISTICS

Typical Performance Curves Unless Otherwise Specified (Continued)

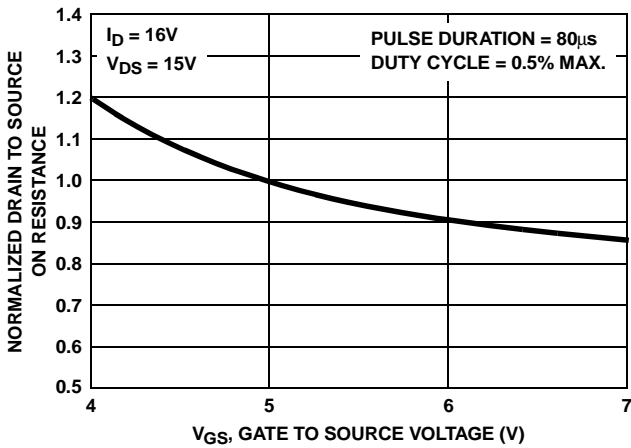


FIGURE 7. DRAIN TO SOURCE ON RESISTANCE vs GATE VOLTAGE AND DRAIN CURRENT

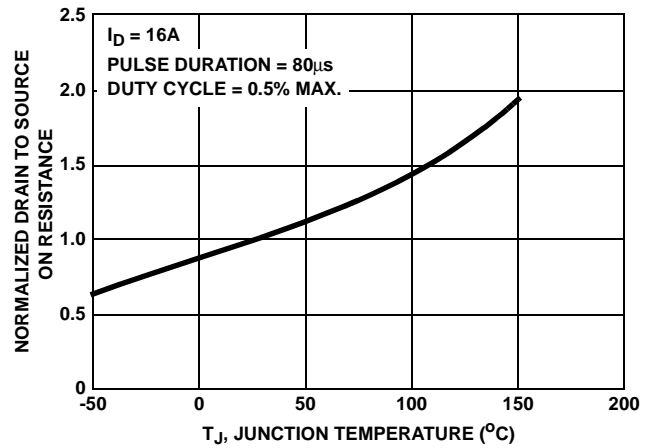


FIGURE 8. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

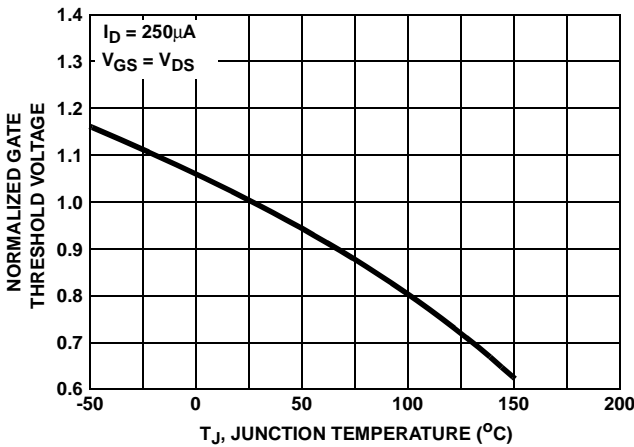


FIGURE 9. NORMALIZED GATE THRESHOLD vs JUNCTION TEMPERATURE

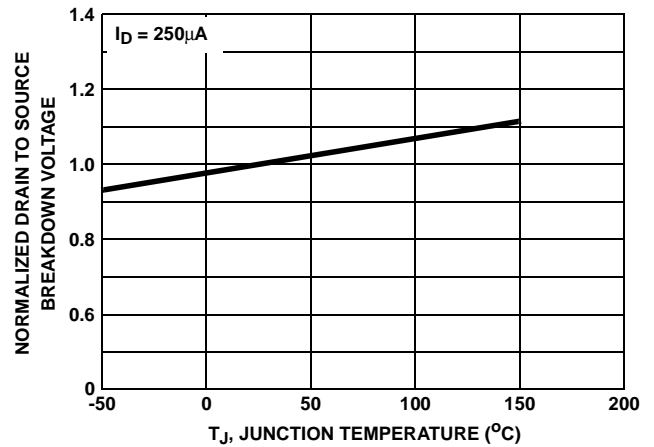


FIGURE 10. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

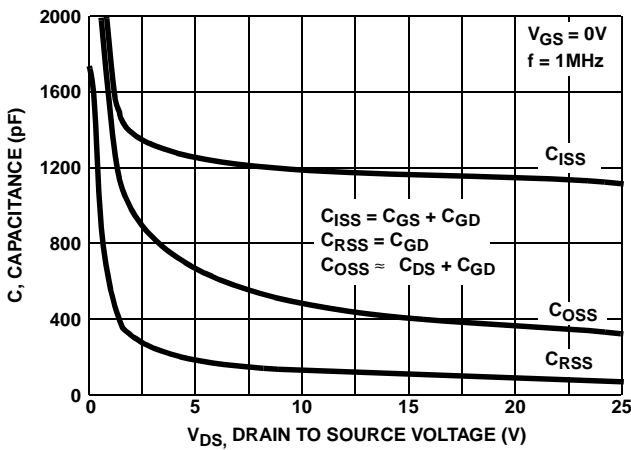


FIGURE 11. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

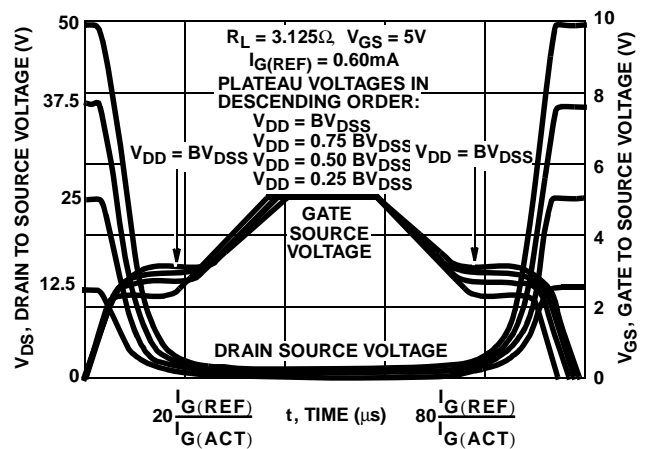


FIGURE 12. NORMALIZED SWITCHING WAVEFORMS FOR CONSTANT GATE CURRENT

Test Circuits and Waveforms

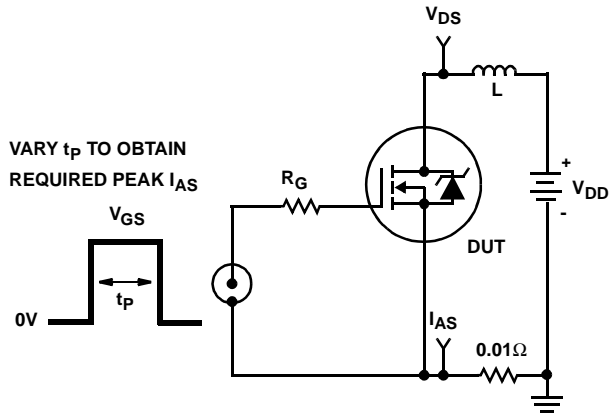


FIGURE 13. UNCLAMPED ENERGY TEST CIRCUIT

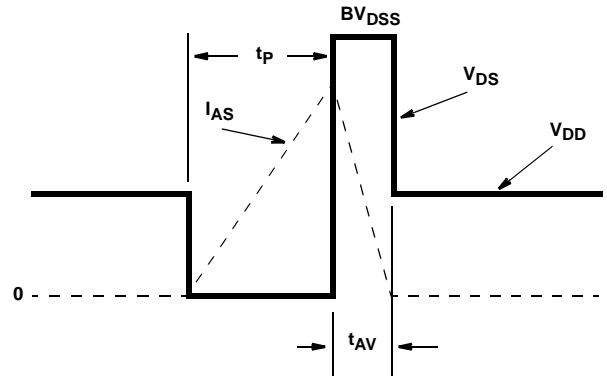


FIGURE 14. UNCLAMPED ENERGY WAVEFORMS

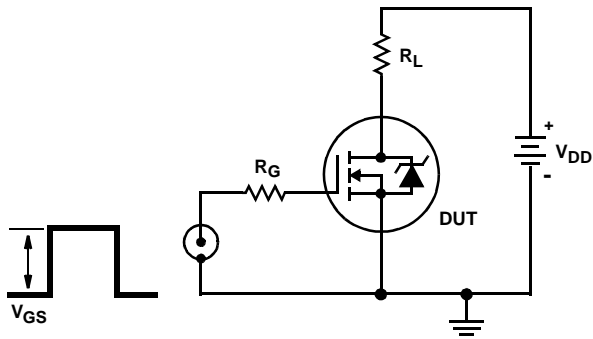


FIGURE 15. SWITCHING TIME TEST CIRCUIT

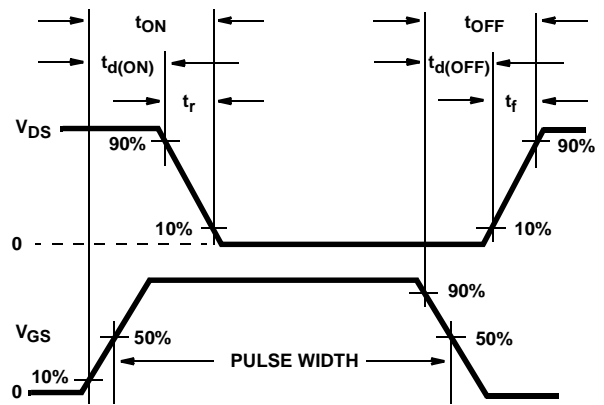


FIGURE 16. RESISTIVE SWITCHING WAVEFORMS

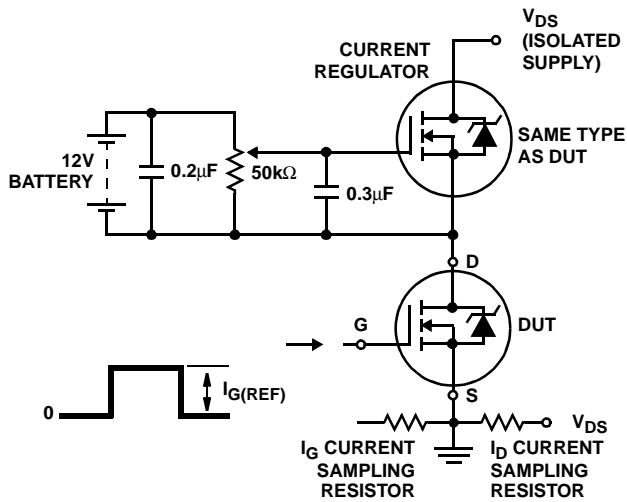


FIGURE 17. GATE CHARGE TEST CIRCUIT

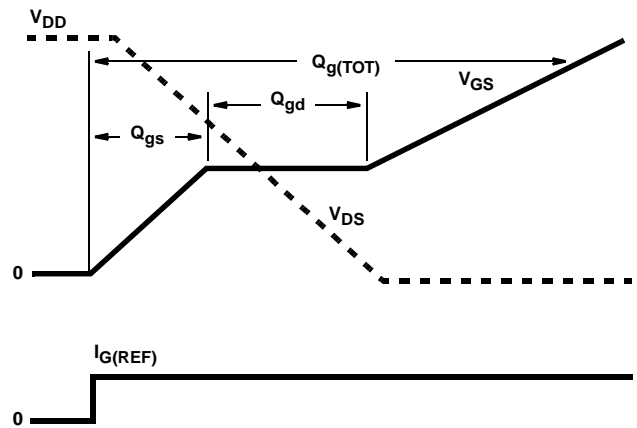


FIGURE 18. GATE CHARGE WAVEFORMS



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